

PolarHT[™] Power MOSFET

IXTK 200N10P

 $V_{DSS} = 100 V$ $I_{D25} = 200 A$ $R_{DS(op)} \le 7.5 m\Omega$

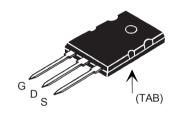
N-Channel Enhancement Mode Avalanche Rated



Symbol	Test Conditions	Maximum	Maximum Ratings		
V _{DSS} V _{DGR}	$T_{_{\rm J}}$ = 25° C to 175° C $T_{_{\rm J}}$ = 25° C to 175° C; $R_{_{\rm GS}}$ = 1 MΩ	100 100	V		
V _{GS} V _{GSM}	Continuous Transient	±20 ±30	V		
I _{D25}	T _c =25°C External lead current limit	200 75	A		
I _{D(RMS)}	$T_{\rm c}$ = 25° C, pulse width limited by $T_{\rm JM}$	400	A		
I _{AR}	T _C =25°C	60	Α		
\mathbf{E}_{AR}	T _C = 25° C	100	mJ		
E _{AS}	T _C =25°C	4	J		
dv/dt	$I_{S} \leq I_{DM}, \text{ di/dt } \leq 100 \text{ A/}\mu\text{s}, \text{ V}_{DD} \leq \text{V}_{DSS},$ $T_{J} \leq 150^{\circ}\text{ C}, \text{ R}_{G} = 4 \Omega$	10	V/ns		
P _D	T _C =25°C	800	W		
T _J T _{JM} T _{stg}		-55 +175 175 -55 +150	°C °C °C		
T _L T _{SOLD}	1.6 mm (0.062 in.) from case for 10 s Plastic body for 10 s	300 260	°C		
M _d	Mounting torque	1.13/10	Nm/lb.in.		
Weight		10	g		

Symbol (T _J = 25° C,	Test Conditions unless otherwise specified)			aracteri Typ.	istic Val	
BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		100			V
V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 500 \mu A$		2.5		5.0	V
I _{GSS}	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$				±200	nA
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 150° C			25 250	μ Α μ Α
R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 0.5 I_{D25}$ $V_{GS} = 15 \text{ V}, I_{D} = 400 \text{A}$ Pulse test, t \le 300 \mus, duty	cycle d ≤ 2 %		5.5	7.5	mΩ mΩ

TO-264 (IXTK)



G = Gate D = Drain S = Source TAB = Drain

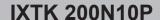
Features

- ¹ International standard package
- ¹ Unclamped Inductive Switching (UIS) rated
- 1 Low package inductance
 - easy to drive and to protect

Advantages

- ^I Easy to mount
- Space savings
- High power density

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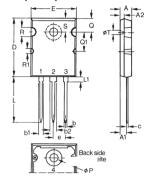
Symbol **Test Conditions Characteristic Values** (T₁ = 25° C, unless otherwise specified) Min. Max. Typ. V_{DS} = 10 V; I_{D} = 0.5 I_{D25} , pulse test 97 S \mathbf{g}_{fs} рF Ciss 7600 $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ 2900 рF $\mathbf{C}_{\underline{\mathsf{rss}}}$ 860 рF t_{d(on)} 30 ns V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS} , I_{D} = 60 A t, 35 ns $R_c = 3.3 \Omega$ (External) 150 ns t_{d(off)} 90 t, ns $\boldsymbol{\mathsf{Q}_{\mathsf{g(on)}}}$ 240 nC \mathbf{Q}_{gs} V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS} , I_{D} = 0.5 I_{D25} 50 nC \mathbf{Q}_{qd} 135 nC R_{thJC} 0.18°C/W °C/W 0.15 $\mathbf{R}_{\mathrm{thCS}}$

Source-Drain Diode

Characteristic Values (T, = 25°C, unless otherwise specified)

Symbol		Test Conditions	Min.	∣Тур.	Max.	
Is		V _{GS} = 0 V			200	Α
I _{sm}		Repetitive			400	Α
$\mathbf{V}_{\mathtt{SD}}$		$I_F = I_S$, $V_{GS} = 0$ V, Pulse test, t ≤300 μ s, duty cycle d≤ 2 %			1.5	V
t _{rr} Q _{RM}	}	$I_F = 25 \text{ A}, -di/dt = 100 \text{ A/}\mu\text{s}$ $V_R = 50 \text{ V}, V_{GS} = 0 \text{ V}$		100 3.0		ns μC

TO-264 (IXTK) Outline



Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
Α	4.82	5.13	.190	.202
A1	2.54	2.89	.100	.114
A2	2.00	2.10	.079	.083
b	1.12	1.42	.044	.056
b1	2.39	2.69	.094	.106
b2	2.90	3.09	.114	.122
С	0.53	0.83	.021	.033
D	25.91	26.16	1.020	1.030
Е	19.81	19.96	.780	.786
е	5.46	5.46 BSC		BSC
J	0.00	0.25	.000	.010
K	0.00	0.25	.000	.010
L	20.32	20.83	.800	.820
L1	2.29	2.59	.090	.102
Р	3.17	3.66	.125	.144
Q	6.07	6.27	.239	.247
Q1	8.38	8.69	.330	.342
R	3.81	4.32	.150	.170
R1	1.78	2.29	.070	.090
S	6.04	6.30	.238	.248
T	1.57	1.83	.062	.072

Fig. 1. Output Characteristics

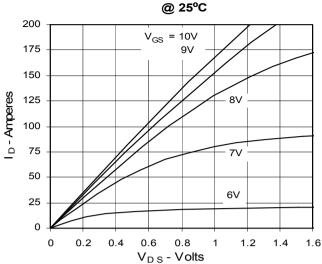


Fig. 3. Output Characteristics @ 150°C

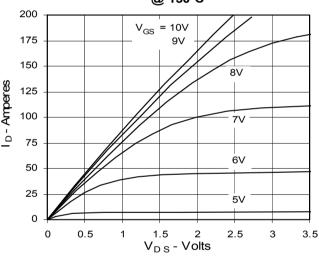


Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Drain Current

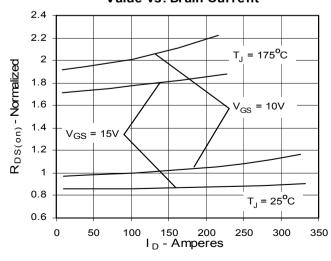


Fig. 2. Extended Output Characteristics @ 25°C

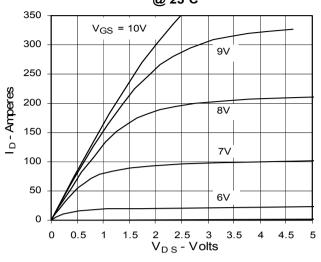


Fig. 4. R_{DS(on)} Normalized to 0.5 I_{D25} Value vs. Junction Temperature

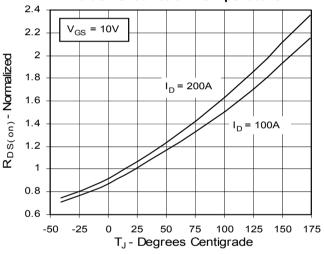
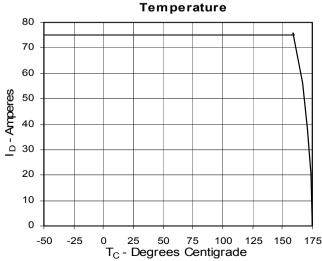
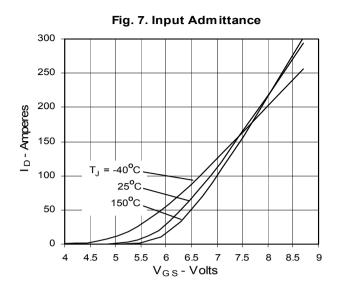
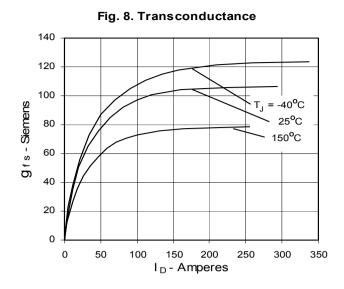


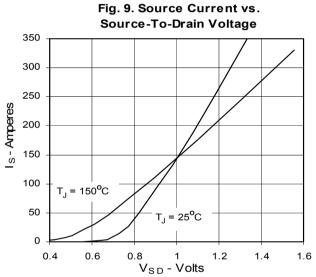
Fig. 6. Drain Current vs. Case

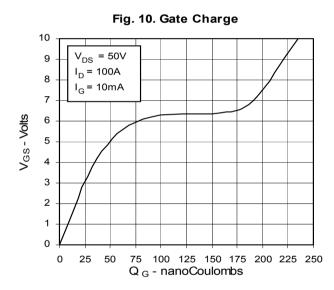


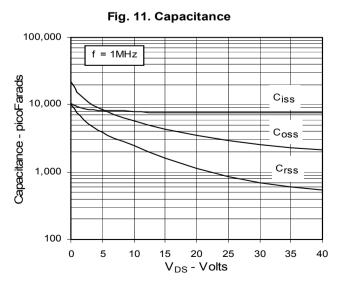


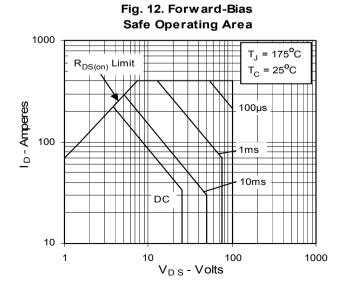












IXYS reserves the right to change limits, test conditions, and dimensions.



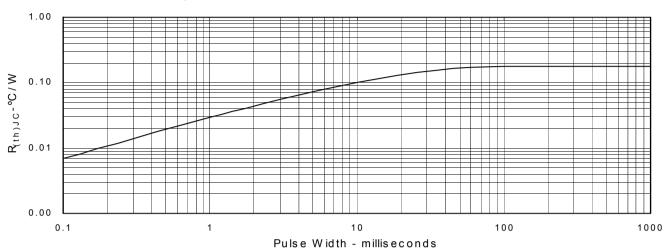


Fig. 13. Maximum Transient Thermal Resistance

